

2SD0874, 2SD0874A (2SD874, 2SD874A)

Silicon NPN epitaxial planar type

For low-frequency power amplification

Complementary to 2SB0766 (2SB766) and 2SB0766A (2SB766A)

Features

- Large collector power dissipation P_C
- Low collector-emitter saturation voltage $V_{CE(sat)}$
- Mini power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing

Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	2SD0874	30	V
	2SD0874A	60	
Collector-emitter voltage (Base open)	2SD0874	25	V
	2SD0874A	50	
Emitter-base voltage (Collector open)	V_{EBO}	5	V
Collector current	I_C	1	A
Peak collector current	I_{CP}	1.5	A
Collector power dissipation *	P_C	1	W
Junction temperature	T_j	150	$^\circ C$
Storage temperature	T_{stg}	-55 to +150	$^\circ C$

Note) *: Printed circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion

Electrical Characteristics $T_a = 25^\circ C \pm 3^\circ C$

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-base voltage (Emitter open)	2SD0874	$I_C = 10 \mu A, I_E = 0$	30			V
	2SD0874A		60			
Collector-emitter voltage (Base open)	2SD0874	$I_C = 2 mA, I_B = 0$	25			V
	2SD0874A		50			
Emitter-base voltage (Collector open)	V_{EBO}	$I_E = 10 \mu A, I_C = 0$	5			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 20 V, I_E = 0$			0.1	μA
Forward current transfer ratio *1	h_{FE1} *2	$V_{CE} = 10 V, I_C = 500 mA$	85		340	—
	h_{FE2}	$V_{CE} = 5 V, I_C = 1 A$	50			
Collector-emitter saturation voltage *1	$V_{CE(sat)}$	$I_C = 500 mA, I_B = 50 mA$		0.2	0.4	V
Base-emitter saturation voltage *1	$V_{BE(sat)}$	$I_C = 500 mA, I_B = 50 mA$		0.85	1.2	V
Transition frequency	f_T	$V_{CB} = 10 V, I_E = -50 mA, f = 200 MHz$		200		MHz
Collector output capacitance (Common base, input open circuited)	C_{ob}	$V_{CB} = 10 V, I_E = 0, f = 1 MHz$			20	pF

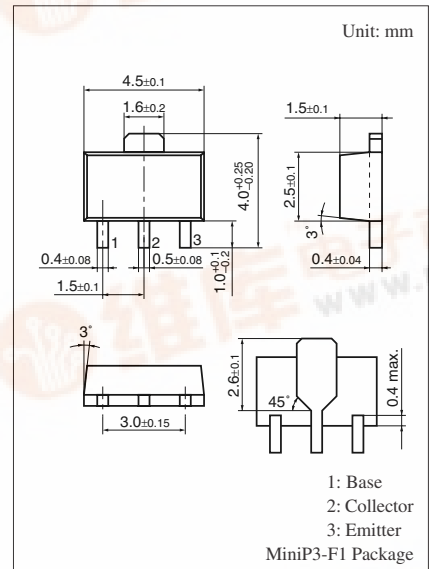
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *1: Pulse measurement

*2: Rank classification

Rank	Q	R	S
h_{FE1}	85 to 170	120 to 240	170 to 340

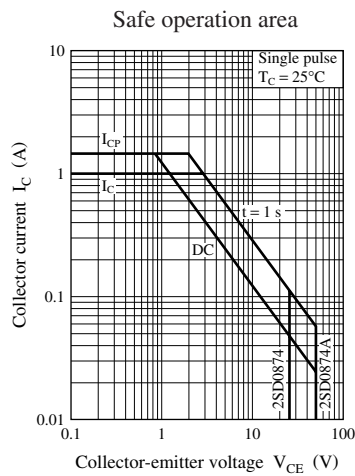
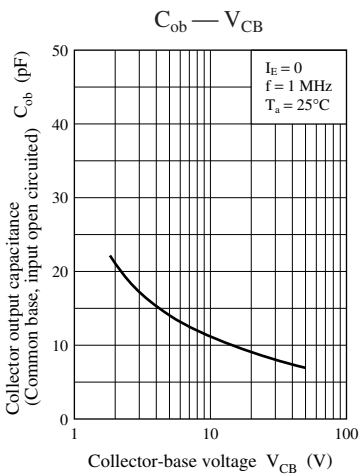
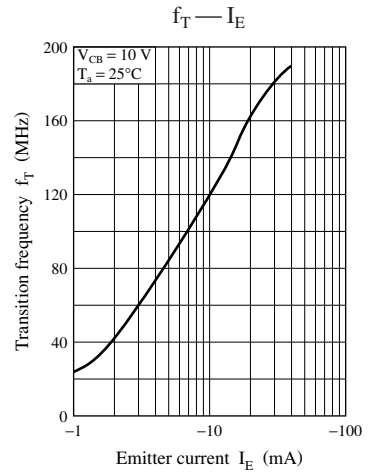
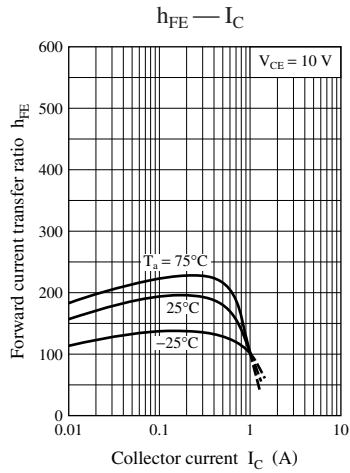
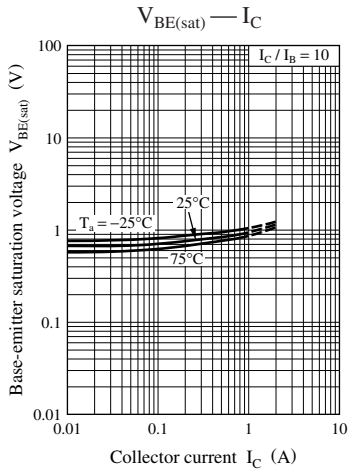
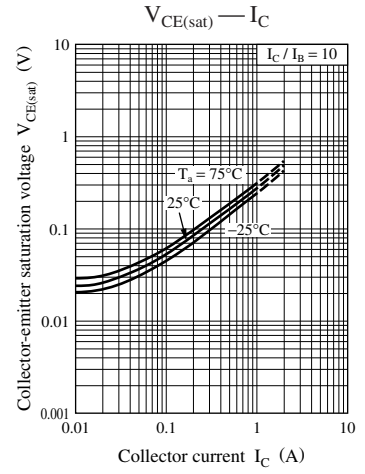
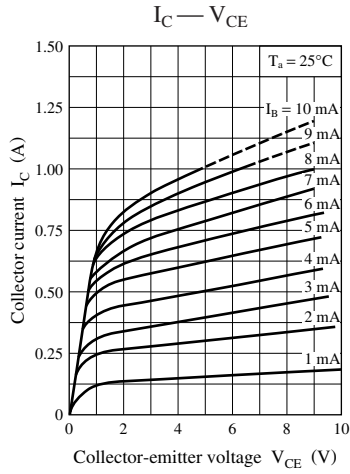
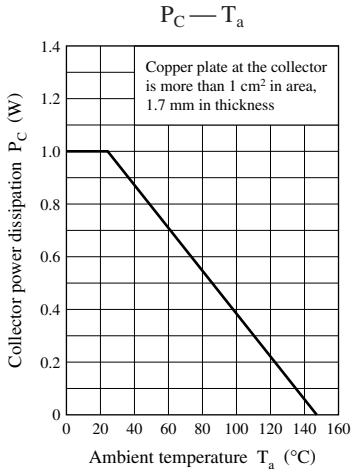
Note) The part numbers in the parenthesis show conventional part number.



Marking Symbol:

- 2SD0874: Z
- 2SD0874A: Y





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